



09/692606

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PATENTS

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Applicant: Jack Oon Chu, et al.

Docket: 17178

Patent No.: 6,890,835

Dated: August 04, 2005

Issued: May 10, 2005

**For: LAYER TRANSFER OF LOW DEFECT SIGE
USING AN ETCH-BACK PROCESS**

**Commissioner for Patents
P.O. Box 1450
Alexandria, VA 22313-1450**

REQUEST FOR CERTIFICATE OF CORRECTION

Sir:

**It appears that errors have been introduced in the course of printing the
Patent issued in the above application, and it is respectfully requested that the
Commissioner issue a Certificate of Correction in the following respects:**

[57] ABSTRACT (Last Sentence)

"contact of the SiGe/Si" should read -- contact of the SiGe/Si --

**Certificate
AUG 12 2005
of Correction**

Respectfully submitted,

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**UNITED STATES PATENT AND TRADEMARK OFFICE
CERTIFICATE OF CORRECTION**

PATENT NO : 6,890,835 *B1*
APPLICATION NO : 09/692,606
ISSUE DATE : May 10, 2005
INVENTOR(S) : Jack Oon Chu, et al.

It is certified that an error appears or errors appear in the above-identified patent and that said Letters Patent is hereby corrected as shown below:

[57] ABSTRACT (Last Sentence)

“contact of the SiGe/Si” should read -- contact of the SiGe/Si --

MAILING ADDRESS OF SENDER:

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PATENT NO. 6,890,835

No. of additional copies

1